
**Surface chemical analysis — X-ray
photoelectron spectroscopy —
Measurement of silicon oxide
thickness**

*Analyse chimique des surfaces — Spectroscopie de photoélectrons par
rayons X — Mesurage de l'épaisseur d'oxyde de silicium*

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This second edition cancels and replaces the first edition (ISO 14701:2011), which has been technically revised.

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